

## ABSTRACT OF THE DISCLOSURE

A test apparatus 10 according to the present invention includes: a plurality of test modules 150, connected to either  
5 of the plurality of devices under test 100, for supplying a test signal to the connected device under test 100; a plurality of control apparatuses 130 for controlling the plurality of test modules 150, and for testing the plurality of devices under test 100 in parallel; and a connection setting section 140 for  
10 switching topology of the plurality of control apparatuses 130 and the plurality of test modules 150 so that the plurality of control apparatuses 10 connect with the plurality of devices under test 100 respectively.

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